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Contents of Volume 24

NUMBER 1 JANUARY 1996

FTIR and XPS Studies on Corrosion-resistant SiO_2 Coatings as a Function of the Humidity during Deposition 1
R. HOFMAN, J. G. F. WESTHEIM, I. POUWEL, T. FRANSEN AND P. J. GELLINGS

Topographic Changes on the Surfaces of PVD Coatings in Humid Air: an AFM/LFM Study 7
Th. SCHNEIDER, G. MEIER, Zu KÖCKER AND E. SANTNER

Backscattering Factor for KLL Auger Yield from Film–Substrate Systems 15
C. L. LEE, K. Y. KONG, H. GONG AND C. K. ONG

Enhanced Resolution of Depth Profiles Using Two-dimensional XPS Data 23
K. L. AMINOV, J. S. JØRGENSEN AND J. BOIDEN PEDERSEN

Differential Charging in XPS Part I: Demonstration of Lateral Charging in a Bulk Insulator Using Imaging XPS 28
B. J. TIELSCH AND J. E. FULGHUM

On the Use of LEIS to Determine Concentration Depth Profiles in Binary Alloys: Application to PtNi(111) 34
J. C. BERTOLINI, P. DELICHÈRE AND P. HERMANN

A Universal Predictive Equation for the Inelastic Mean Free Pathlengths of X-ray Photoelectrons and Auger Electrons 38
W. H. GRIES

Surface Modification of Electroactive Polymer Films By Ozone Treatment 51
E. T. KANG, K. G. NEOH, X. ZHANG, K. L. TAN AND D. J. LIAW

Effects of Polypeptide Conformation and Surface Bonding on Static Secondary Ion Mass Spectra 59
C. G. WORLEY, E. P. ENRIQUEZ, E. T. SAMULSKI AND R. W. LINTON

Determination of the Absolute Density of Fe^{3+} and Ni^{2+} Ions in Langmuir–Blodgett Films 68
T. FALDUM, W. MEISEL AND P. GÜTLICH

NUMBER 2 FEBRUARY 1996

Preface 77
J. T. GRANT

Surface Analysis with 10^{14}–10^{15} W cm^2 Laser Intensities 79
C. HE AND C. H. BECKER

Advantages of a High-frequency Square Wave in a Sputtered Neutral Mass Spectrometry Study of Insulating Materials 86
T. A. DANG, T. A. FRISK AND J. K. NESBELLA

XPS Studies of Fluorine Bonding in Phosphate Glasses 91
R. K. BROW AND Z. A. OSBORNE

The Nitridation of a Silicon Powder Studied by XPS and X-ray-induced AES 95
P. S. WANG AND T. N. WITTBERG

X-ray Photoelectron Spectroscopic Study of the Possible Interactions of Biocells with the Surfaces of Select Silicates 99
T. L. BARR, S. SEAL, S. KREZOSKI AND D. H. PETERING

XPS Characterization of *In situ* Prepared Ti/Glass Interfaces 113
S. K. SAHA, H. JAIN, A. C. MILLER AND R. K. BROW

Impurity Tracing of Diffusion Mechanisms in Hillock Growth on Aluminum Films 119
N. D. ROSEN

XPS Study of the Oxidation Behavior of the Cu_3Sn Intermetallic Compound at Low Temperatures 127
D. N. WANG, A. C. MILLER AND M. R. NOTIS

Spectroscopic Parameters of the Heteronuclear Diatomic Molecules of Ni, Pd, Pt, Cu, Ag and Au 133
C. W. FINLEY AND J. FERRANTE

Coverage-dependent Bond Length of Chlorine Adsorbed on Cu{111} 137
W. K. WAY, A. C. PIKE, S. W. ROSENCRANCE, R. M. BRAUN AND N. WINOGRAD

NUMBER 3 MARCH 1996

High-temperature Oxidation of Carborane–Siloxane–Acetylene-based Polymer 145
P. E. PEHRSSON, L. J. HENDERSON AND T. M. KELLER

Sources of Internal Scattering of Electrons in a Cylindrical Mirror Analyser (CMA) 152
M. M. EL GOMATI AND T. A. EL BAKUSH

Spectrum Synthesis Based on Non-linear Addition 163
T. A. EL BAKUSH AND M. M. EL GOMATI

Analysis of Multispectral Microscope Images Using Neural Networks 173
C. G. H. WALKER

XPS Characterization of the Corrosion Films Formed on Nanocrystalline Ni–P Alloys in Sulphuric Acid 181
S. J. SPLINTER, R. ROFAGHA, N. S. MCINTYRE AND U. ERB

XPS Imaging of Patterned Self-assembled Monolayers Containing Perfluorinated Alkyl Chains 187
S. D. EVANS, T. M. FLYNN, A. ULMAN AND G. BEAMSON

Prevention of the Reduction of CuO during X-ray Photoelectron Spectroscopy Analysis 193
Y. IIJIMA, N. NIIMURA AND K. HIRAOKA

Use of the Peak-to-background Ratio for Quantitative Auger Analysis of Semi-insulating Polycrystalline Silicon Layers 198
J. LIDAY, S. TOMEK, P. VOGRINČIČ, P. MRÁZIK AND J. BREZA

Characterisation of PTFE on Silicon Wafer Tribological Transfer Films by XPS, Imaging XPS and AFM 204
G. BEAMSON, D. T. CLARK, D. E. DEEGAN, N. W. HAYES, D. S.-L. LAW, J. R. RASMUSSON AND W. R. SALANECK

Estimation of Excitation Depth Distribution from Electron-excited Auger Spectra of Iron Using Peak Shape Analysis 211
D. FUJITA, M. SCHLEBERGER AND S. TOUGAARD

Short Communication
Trifluoroethanol Derivatization of Carboxylic Acid-containing Polymers for Quantitative XPS Analysis 217
M. R. ALEXANDER, P. V. WRIGHT AND B. D. RATNER

NUMBER 4 APRIL 1996

X-ray Photoelectron Spectroscopic Study of Petroleum Fuel Cokes 223
J. M. JIMÉNEZ MATEOS AND J. L. G. FIERRO

Hardening Process and Surface Structure of Lacquer Films Studied by X-ray Photoelectron Spectroscopy 237
N. NIIMURA, Y. IIJIMA AND T. MIYAKOSHI

Comparative Study of SIMOX Structures Using Four Analytical Techniques 243
W. FUKAREK, R. A. YANKOV AND W. SKORUPA

XPS and SERS Studies of Cell Adhesion-controlled Polymer Modified by Ion Implantation 252
A. NAKAO, M. KAIBARA, M. IWAKI, Y. SUZUKI AND M. KUSAKABE

Determination of Functional Groups on Polymer Surfaces Using Fluorescence Labelling 257
V. B. IVANOV, J. BEHNISCH, A. HOLLÄNDER, F. MEHDORN AND H. ZIMMERMANN

Quantitative AES Analysis of Fracture Surfaces in the Presence of O- and C-containing Residual Gas 263
U. OTTERBEIN AND S. HOFMANN

Characterisation of the Ageing of Plasma-deposited Polymer Films: Global Analysis of X-ray Photoelectron Spectroscopy Data 271
T. R. GENGENBACH, R. C. CHATELIER AND H. J. GRIESSER

Determination of Fractured Steel Surface Roughness by Atomic Force Microscopy Using Fractal-based Approaches 282
PH. GOLLION AND G. GRENET

Glancin-Incidence and -Take-off X-ray Fluorescence and Scanning Tunnelling Microscopy of Thin Films Under X-ray Irradiation 286
K. TSUJI AND K. HIROKAWA

NUMBER 5 MAY 1996

Characterisation of Films Grown on Aluminium Immersed in Aerated Saline Solutions Containing Nickel 293
A. N. RIDER, D. R. ARNOTT, A. R. WILSON, I. DANILIDIS AND P. J. K. PATERSON

Surface Coverage of Rhenium–Alumina Catalysts 306
F. M. MULCAHY, J. GOLDWASSER, A. PROCTOR, M. HOUALLA AND D. M. HERCULES

XPS/ISS Investigation of Carbon Fibers Sequentially Exposed to Nitric Acid and Sodium Hydroxide 311
S. D. GARDNER, C. S. K. SINGAMSETTY, Z. WU AND C. U. PITTMAN, JR.

Formation of Active Carbon Layers on Pt(111) by Electron Bombardment of CO 321
S. STEFFENATO, G. COMELLI, R. ROSEI, A. BARALDI, G. PAOLUCCI AND M. KISKINOVA

Calculation of Surface Peak Intensity of GaAs and InP in High-energy Ion Scattering 327
H. OHYAMA, T. NARUSAWA AND H. NAKASHIMA

A Closed Specimen Transfer for Surface Analytical Application 332
J.-M. ABELS, D. HECHT AND H.-H. STREHBLOW

Study of the Interface between Polyacrylonitrile Thin Films and a Nickel Cathode: Ni 3d States Analyzed by EXES 339
P. JONNARD, F. VERGAND, P.-F. STAUB, C. BONNELLE, G. DENIAU, C. BUREAU AND G. LECAYON

Interaction of SO_2 with Different Polycrystalline Cu, Cu_2O, CuO Surfaces 345
A. GALTAYRIES, J. GRIMBLOT AND J.-P. BONNELLE

Photo-induced Transformation, upon UV Illumination in Air, of Hyponitrite Species, $N_2O_2^{2-}$, Preadsorbed on TiO_2 Surface 355
J. A. NAVIO, C. CERRILLOS AND C. REAL

NUMBER 6 JUNE 1996

Surface Analysis by SNMS: Femtosecond Laser Postionization of Sputtered and Laser Desorbed Atoms 363
G. K. NICOLUSSI, M. J. PELLIN, K. R. LYKKE, J. L. TREVOR, D. E. MENCER AND A. M. DAVIS

Factors Affecting the Quantification of Boron in SiO_2 and Si by Sputtered Neutral Mass Spectrometry 371
M. L. WISE, N. MORIYA AND S. W. DOWNEY

Auger Electron Spectroscopy of Boron Nitride in Hot-Rolled Graphitized Steel Sheet 375
T. MEGA, R. MORIMOTO, T. MORITA AND J.-I. SHIMOMURA

Surface Characterization of EMA Copolymers Using XPS and ToF-SIMS 380
A. GALUSKA

Sputtering Yield Changes, Surface Movement and Apparent Profile Shifts in SIMS Depth Analyses of Silicon Using Oxygen Primary Ions 389
K. WITTMAACK

An All-optical Mass Spectrometric System Based on Picosecond-Laser Pulses 399
M. SCHÜTZE, C. TRAPPE, M. TABELLION, G. LÜPKE AND H. KURZ

Innovative Methods for a Deconvolution of XPS Spectra from Plasma-oxidized Polyethylene 405
S. MÄHL, J. LACHNITT, R. NIEMANN, M. NEUMANN, A. BAALMANN, A. KRUSE AND V. SCHLETT

CEMS and AES Investigations on Iron Silicides 411
H. REUTHER AND M. DOBLER

Effect of Ion Beam Mixing and Compound Formation on Sputter Depth Profile of a Ta/Si Multilayer Thin Film 416
M. G. STEPANOVA

Short Communication
Surface Morphology of PVC/PMMA Blend Studied by ToF-SIMS 419
D. BRIGGS, I. W. FLETCHER, S. REICHLMAIER, J. L. AGULO-SANCHEZ AND R. D. SHORT

Errata
Differential Charging in XPS. Part I: Demonstration of Lateral Charging in a Bulk Insulator Using Imaging XPS 422
B. J. TIELSCH AND J. E. FULGHUM

Letter to the Editor
Curve-Fitting Errors in the Article 'Backscattering Factor for KLL Auger Yield from Film–Substrate Systems' by C. L. Lee *et al.* [*Surf. Interface Anal.*, **24**, 15 (1996)] 428
C. L. LEE

NUMBER 7 JULY 1996

Ion-implanted Surface Analysis Reference Materials: Certification of Dose Densities from 10^{16} to 10^{13} cm^{-2} 431
W. H. GRIES

Electrochemical Oxidation of ZrN Hard (PVD) Coatings Studied by XPS 448
I. MILOŠEV, H.-H. STREHBLOW, M. GABERŠČEK AND B. NAVINŠEK

Differential Charging in XPS. Part II: Sample Mounting and X-ray Flux Effects on Heterogeneous Samples 459
B. J. TIELSCH, J. E. FULGHUM AND D. J. SURMAN

SIMS Depth Profiling of Delta-doped Layers in Silicon 469
V. K. SMIRNOV, S. G. SIMAKIN, E. V. POTAPOV AND V. V. MAKAROV

Study of Low-energy Atomic Mixing by Means of Auger Depth Profiling, XTEM and TRIM Simulation on Ge/Si Multilayer System 476
A. BARNA AND M. MENYHARD

NUMBER 8 AUGUST 1996

Towards a 3D Characterization of Solids by MCs^+ SIMS 483
H. GNASER

Role of Surface Effects in the Inelastic Background of X-ray Photoelectron Spectroscopy 490
Y. F. CHEN AND Y. T. CHEN

Atomic Force Microscopy Investigation of Noble Gas Ion Bombardment on InP: Effect of Ion Energy 497
C. M. DEMANET, K. V. SANKAR, J. B. MALHERBE, N. G. VAN DER BERG AND R. Q. ODENDAAL

Atomic Force Microscopy Investigation of Ion-bombarded InP: Effect of Angle of Ion Bombardment 503
C. M. DEMANET, K. V. SANKAR AND J. B. MALHERBE

Characterization and Application of the Vapor Phase Decomposition Technique for Trace Metal Analysis on Silicon Oxide Surface 511
L. H. HALL, J. A. SEES AND B. L. SCHMIDT

Comparison of X-ray-excited Auger lineshapes of Graphite, Polyethylene and Diamond 517
A. P. DEMENTJEV AND M. N. PETUKHOV

Determination of Negative Binding Sites on Hair Surfaces Using XPS and Ba^{2+} Labeling 522
M. A. STRANICK

Letter to the Editor

Comment on 'Curve Fitting of Cr2p Photoelectron Spectra of Cr_2O_3 and CrF_3' 529
A. R. PRATT AND N. S. MCINTYRE

NUMBER 9 16 SEPTEMBER 1996

Preface 533
R. LAMB AND J. LIESEGANG

Fermi Surface of Disordered Cu_3Au as Determined by Angle-resolved Photoemission 535
J. A. CON FOO, S. TKATCHENKO, A. P. J. STAMPFL, A. ZIEGLER, B. MATTERN, M. HOLLERING, R. DENECKE, L. LEY, J. D. RILEY AND R. C. G. LECKEY

Formation of Silicate Structures in Oxidized Nickel Surfaces Using Low-temperature Plasma Reaction 539
P. S. ARORA AND R. St. C. SMART

Detection and Characterization of Dimethylethanolamine-based Corrosion Inhibitors at Steel Surfaces. (I) The Use of XPS and ToF-SIMS 549
C. R. BRUNDLE, M. GRUNZE, U. MÄDER AND N. BLANK

X-ray Photoelectron Spectroscopic Studies of Sulphur-passivated GaAs Surfaces 564
X. WANG, X.-Y. HOU, Z.-S. LI AND X.-Y. CHEN

Effect of Contaminant on the Durability of Epoxy Adhesive Bonds with Alclad 2024 Aluminium Alloy Adherends 569
C. L. OLSSON-JACQUES, A. R. WILSON, A. N. RIDER AND D. R. ARNOTT

Angle-dependent XPS Analysis of $(NH_4)_2Sx$-treated InP(001) Surfaces 578
Y. FUKUDA, Y. SUZUKI, N. SANADA AND S. SASAKI

Durability of Bonds Formed Between Epoxy Adhesive and Aluminium Alloy Treated with Phosphonate Inhibitors 583
A. N. RIDER AND D. R. ARNOTT

Quantitative XPS Measurements of Some Oxides, Sulphides and Complex Minerals 591
N. S. McINTYRE, R. D. DAVIDSON AND J. R. MYCROFT

XPS Characterization of Surface Functionalized Electroactive Polymers 597
F. C. LOH, K. L. TAN, E. T. KANG, K. KATO, Y. UYAMA AND Y. IKADA

X-ray Photoelectron Spectroscopy Study of Optical Waveguide Glasses 605
M. H. KIBEL AND P. W. LEECH

Correlation of the Nitrogen 1s and Oxygen 1s XPS Binding Energies with Compositional Changes During Oxidation of Ethylene Diamine Plasma Polymers 611
T. R. GENGENBACH, R. C. CHATELIER AND H. J. GRIESSER

Irradiation Effects During XPS Studies of Cu(II) Activation of Zinc Sulphide 620
W. M. SKINNER, C. A. PRESTIDGE AND R. St. C. SMART

Characterisation of the Optical Properties and Composition of TiN_x Thin Films by Spectroscopic Ellipsometry and X-ray Photoelectron Spectroscopy 627
A. BENDAVID

Unusual Peak Shifts in the Core Levels of CeO_2 Films Deposited on Si(100) 634
A. E. HUGHES, J. D. GORMAN, P. J. K. PATTERSON AND R. CARTER

XPS Evidence for the Incongruent Surface Oxidation of Minerals in the Pd-Te-Bi System 641
S. B. ELVY, P. A. WILLIAMS AND A. N. BUCKLEY

XPS Study of Surface Cation Segregation in Mullite/Zirconia Composites 647
Z. ZHANG, J. NOWOTNY, P. J. PIGRAM, R. N. LAMB, S. NAKAMURA AND K. YAMANA

XPS Study of Mn Thin Films Grown on GaAs(001) Surfaces 653
G. S. DONG, M. XU, Y. CHEN, X. F. JIN AND X. WANG

Electronic Structure of $Nd_{0.5}Y_{0.5}Ba_2Cu_3O_{7-\delta}$ Single Crystals 657
A. HARTMANN, G. J. RUSSELL, D. N. MATTHEWS AND J. W. COCHRANE

Structural Characterization of Pd-doped SnO_2 Thin Film Using XPS 662
X. CAO, L. CAO, W. YAO AND X. YE

Comparison of Self-Assembled Monolayers of *n*-Alkanethiols and Phenylthioureas on the Surface of Gold 667
Y. NING, H. XIE, H. XING, W. DENG AND D. YANG

Influence of Copper Dopants on the Resistivity of ZnO Films 671
A. HARTMANN, M. K. PUCHERT AND R. N. LAMB

Investigation of the Interfacial Region Formed During ZnO Growth on Si(100) Substrate Using Single-source CVD 675
M. H. KOCH, G. L. MAR, A. J. HARTMANN AND R. N. LAMB

NUMBER 10 30 SEPTEMBER 1996

Clean Surface and Oxidation Behavior of Vanadium Carbide, $VC_{0.75}(100)$ 681
M. D. ANTONIK, R. J. LAD AND T. M. CHRISTENSEN

Simple Procedure for Precise Peak Maximum Estimation for Energy Calibration in AES and XPS 687
P. J. CUMPSON, M. P. SEAH AND S. J. SPENCER

SIMS Investigation of Fresh and Aged Automotive Exhaust Catalysts 695
A. J. OAKES AND J. C. VICKERMAN

XPS and SIMS Investigation of the Covalently Bound Lipid on the Wool Fibre Surface 704
N. BRACK, R. LAMB, D. PHAM AND P. TURNER

ESCA Analysis of Photodegraded Poly(ethylene terephthalate) Film Utilizing Gas Chemical Modification 711
Y. NAKAYAMA, K. TAKAHASHI AND T. SASAMOTO

Surface Modification of Polyethylene Terephthalate with Excimer UV Radiation 718
J.-Y. ZHANG, I. W. BOYD AND H. ESROM

Crystallisation of PET from the Amorphous State: Observation of Different Rates for Surface and Bulk Using XPS and FTIR 723
N. W. HAYES, G. BEAMSON, D. T. CLARK, D. S.-L. LAW AND R. RAVAL

Letter to the Editor

On the XPS Analysis of Si–OH Groups at the Surface of Silica 729
E. PAPARAZZO

NUMBER 11 OCTOBER 1996

Deconvolution of SIMS Depth Profiles of Boron in Silicon 733
B. GAUTIER, R. PROST, G. PRUDON AND J. C. DUPUY

Static SIMS: A Study of Damage Using Polymers 746
I. S. GILMORE AND M. P. SEAH

Oxidation Study of Dental Metal–Ceramic Alloys by Surface Characterization Techniques Part 2. Pd Alloys 763
J. A. HAUTANIEMI, M. HEINONEN AND J. JUHANOJA

Study of the Silicon/γ-APS/Pyralin Assembly Interfaces by X-ray Photoelectron Spectroscopy 774
I. GEORGE, P. VIEL, C. BUREAU, J. SUSKI AND G. LÉCAYON

Elastic Electron Backscattering from Surfaces at Low Energies 781
A. JABLONSKI AND P. JIRICEK

NUMBER 12 NOVEMBER 1996

Chain End Contribution in Static Secondary Ion Mass Spectrometry of Oligomeric Poly(ethylene glycols) 787
A. G. SHARD, M. C. DAVIES AND E. SCHACHT

Characterization of bis-(phenoxy)phosphazene Polymers Using Static Secondary Ion Mass Spectrometry 794
G. S. GROENEWOLD, R. L. COWAN, J. C. INGRAM, A. D. APPELHANS, J. E. DELMORE AND J. E. OLSON

Polarized Grazing Angle FTIR Study of Molecular Orientation and Bonding of Thioglycolates at the Metal Interface 803
D. B. YANG AND T. WAKAMATSU

Surface Oxidation and Reduction of CuO and Cu_2O Studied Using XPS and XAES 811
S. POULSTON, P. M. PARLETT, P. STONE AND M. BOWKER

Ammonia Plasma Treatment of PTFE Under Known Plasma Conditions 821
S. D. PRINGLE, V. S. JOSS AND C. JONES

Quantitative AES IV: Accuracy of the Numerical Evaluation of Peak Areas in AES using the Universal Tougaard Background Subtraction Method 830
M. P. SEAH

NUMBER 13 DECEMBER 1996

DC-Plasma Polymerization of Hexamethyldisiloxane Part II. Surface and Interface Characterization of Films Deposited on Stainless-steel Substrates 841
S. EUFINGER, W. J. VAN OOIJ AND K. D. CONNERS

Tribological Boron Concentration Profiles at Hard Steel Surfaces Studied by SIMS 856
L. GUDMAND-HØYER, G. T. NIELSEN AND P. MORGEN

Study of the Oxidation States of Chromium in Substituted and Supported Cr-silicoaluminophosphate Molecular Sieves 863
L. GIRALDO, C. PFAFF, C. M. LÓPEZ, F. MACHADO, B. MÉNDEZ, J. GOLDWASSER, M. M. R. DE AGUDELO, S. RONDÓN, M. HOUALLA AND D. M. HERCULES

Depth Profiling by Ion Beams Analysis Techniques for the Characterization of Interdiffusion in Multilayered Au–Al Systems 868
A. MARKWITZ AND G. DEMORTIER

Sulphur Segregation on Polycrystalline Nickel: Artefacts from Crystallographic Effects in the Auger Signal 875
D. R. BATCHELOR, M. DALTON AND G. J. TATLOCK

Ion Impacts and Nanostructures on Ge(111), $In_{0.22}Ga_{0.78}AS/GaAs(100)$ and Alpha Quartz Surfaces Observed by Atomic Force Microscopy 881
I. H. WILSON, Y. J. CHEN, J. B. XU, R. A. B. DEVINE AND C. JEYNES